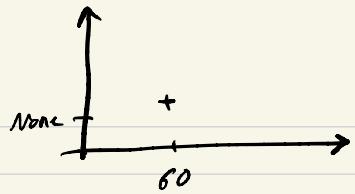


Lecture 13

PAC Learning.

Example 1: Running base on
temperature precipitation

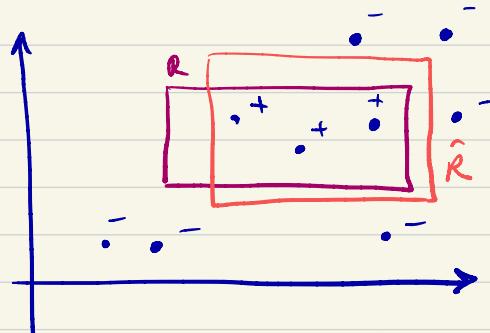


Learning an axis-aligned rectangle R in \mathbb{R}^2

Samples : points $p_1, \dots, p_n \sim D$ over \mathbb{R}^2

label y_1, \dots, y_n

$$y_i = \begin{cases} +1 & \text{if } p_i \in R \\ -1 & \text{otherwise} \end{cases}$$



Goal : output \hat{R} s.t. error of \hat{R} is
small (say ϵ) with high probability
(say $1 - \delta$)

$$\text{err}(\hat{R}) = \Pr_{p \sim D} [\hat{R} \text{ mislabel } p]$$

$$= \Pr_{p \sim D} \left[\begin{array}{ll} (p \in R \text{ and } p \notin \hat{R}) \\ \text{or} \\ (p \notin R \text{ and } p \in \hat{R}) \end{array} \right]$$

D is arbitrary but fix.

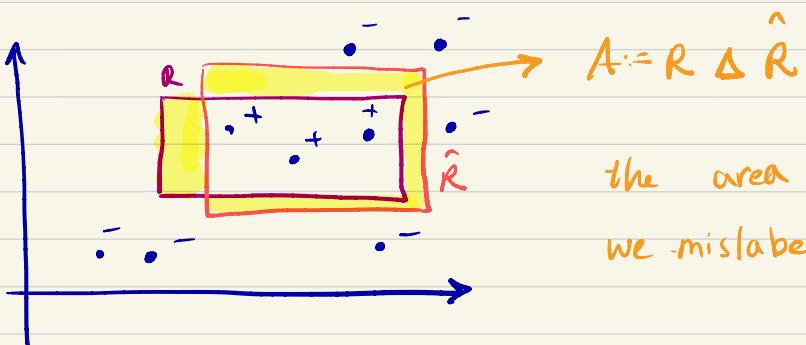
while D can be potentially unusual / irregular,
the notion of error is also defined based
on the same D.

Solution:

Algorithm :

- 1- Draw m samples (for sufficiently large)
- 2- set \hat{R} to be a rectangle that

correctly label all the sample points



$$\text{err}(\hat{R}) = \Pr_{p \sim D} [p \in A] = D(A)$$

by our definition of \hat{R} , there is no sample point in $A := R \Delta \hat{R}$

$$\text{if } \text{err}(\hat{R}) > \epsilon \Rightarrow D(A) > \epsilon$$

How likely it is to not see any sample from A ?

Ideally, we want:

$$\Pr[\# \text{ samples in } A = 0] \stackrel{?}{\leq} \delta$$

$\downarrow D$

$$= (1 - D(A))^m \leq (1 - \epsilon)^m \quad (\text{independent samples})$$
$$\leq e^{-\epsilon m} \quad \text{set } m = \underbrace{\frac{\log \frac{1}{\delta}}{\epsilon}}$$
$$\leq \delta$$

\Rightarrow Hence, with probability at least $1-\delta$
 $\text{err}(\hat{R}) \leq \epsilon.$

$$\left. \begin{array}{l} \text{efficient} \\ \# \text{ samples} = O\left(\frac{\log \frac{1}{\delta}}{\epsilon}\right) \\ \text{time } O(m) \end{array} \right\}$$

Well behaved target class

Probably Approximately Correct (PAC)

X instance space set of all instances
(input space / domain)

c: X → {+1, -1} concept a function to label elements

C concept class a collection of labeling functions

c* target concept $c^* \in C$ and label all instances correctly

D target distribution distribution over instances

sample / training data set } $\langle x_1, c^*(x_1) \rangle$
} $\langle x_2, c^*(x_2) \rangle$
} :
 $\langle x_n, c^*(x_n) \rangle$

+ distribution free setting

samples drawn from an arbitrary distribution.

but error is measured according to the same distribution.

Some papers focus on specific class of distributions such as Gaussians.

+ We say we are in the realizable case if there exists a concept $c^* \in C$ that label all the instances in the domain perfectly

The goal is to find an unknown target concept

c in a known concept class using labeled samples

- find \hat{c} in C with small error w.h. prob.

- Efficiency : # samples & time

PAC learning (Probably Approximately Correct)

Suppose that we have a concept class C over X . We say that C is PAC learnable if there exists an algorithm A s.t:

$$A \in C, \forall D \text{ over } X, \forall \epsilon, \delta \in (0, 0.5]$$

A receives ϵ, δ , and samples $\langle x_1, c(x_1) \rangle, \dots, \langle x_n, c(x_n) \rangle$ where x_i 's are iid samples from D .

Then, w. p. $\geq 1 - \delta$, A outputs \hat{c} s.t.

$$\text{err}(\hat{c}) \leq \epsilon.$$

The probability is taken over the randomness in the samples and any internal coin flips of A .

+ Usually efficiency means :

Sample complexity & time complexity

$$= O(\text{poly}(\frac{1}{\epsilon}, \frac{1}{\delta}))$$

+ ϵ = error parameter

δ = confidence parameter

These two parameters capture two kinds of error:

ϵ : small discrepancy between concepts is not detectable.

δ : with some small probability, the sample set is not representative of reality.